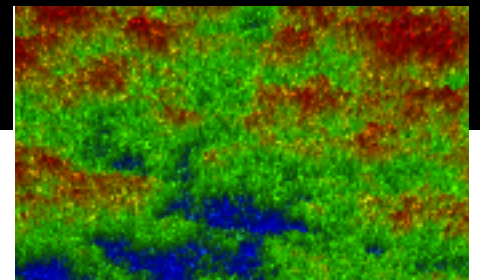
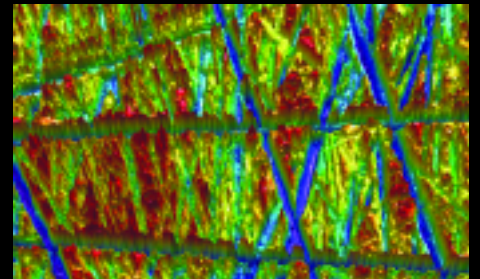
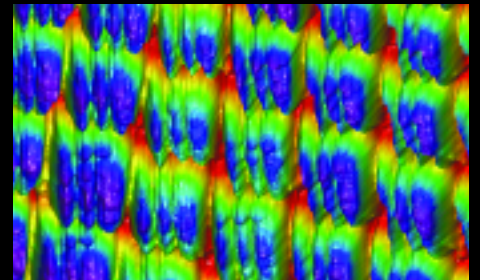


zygo®

600
NewView™



ZYGO CORPORATION'S
NewView™ 600s
3D Optical Profiler

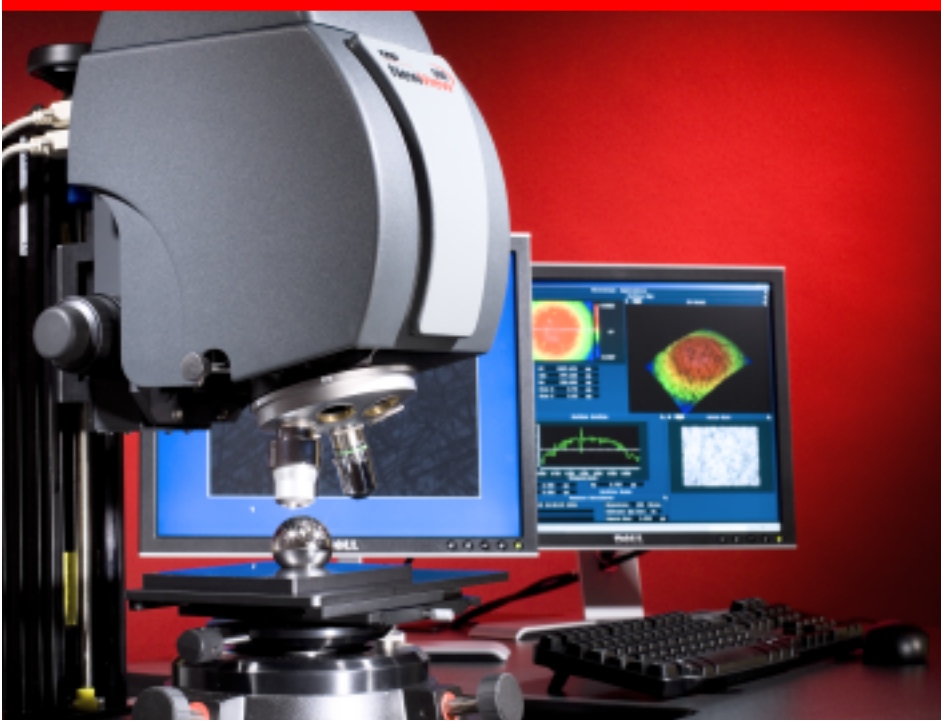


Precision Surface Metrology for Research, Process Control and Quality Assurance

The highly affordable NewView™ 600s provides fast, noncontact, three-dimensional inspection and quantitative surface topography measurement for both research and production applications.

The NewView™ 600s offers high-precision scanning, simplified operation, configuration flexibility, and advanced surface characterization - including comprehensive surface texture, step-height, PSD analysis, and much more. All this in a compact footprint that conserves valuable floor space. In addition, the NewView™ 600s continues to deliver the level of precision and quality that has become the trademark of ZYGO's NewView™ family of products. Simply put, the NewView™ 600s delivers optimal value, in combination with proven precision and quality.

- **Fast, noncontact 3D surface measurements**
- **Sub-angstrom vertical resolution**
- **High precision and reliability**
- **Simple, flexible functionality**
- **Cost-effective, compact platform**



NewView™ 600s Specifications*

SYSTEM

- **Technology** Patented scanning white light interferometry
- **Objectives** 2X, 2.5X, 5X, 10X, 20X, 50X, and 100X; long-working distance versions also available
- **Field-of-View** Selectable from 0.05 to 3.5 millimeters; objective dependent; see Objective Specifications
- **Illuminator** Computer controlled, long life white light LED
- **Measurement Array** 640x480, user selectable
- **Scanner** Closed-loop piezo-based

PERFORMANCE

- **Vertical Resolution** <0.1 nm
- **Lateral Resolution** 0.36 to 5.2 μm
- **Scan Speed** Up to 15 $\mu\text{m}/\text{sec}$
- **Step Height Accuracy** 0.75%
- **Step Height Repeatability** < 0.1%, 1σ
- **Vertical Scan Range** Up to 150 μm

*For full details refer to Specification Sheet SS-0032.

PRECISION — Using ZYGO's patented scanning white-light interferometry technology the NewView 600s easily measures smooth, rough, and stepped surfaces. Profile heights ranging from < 1 nm up to 150 μm with <0.1 nm vertical resolution, independent of surface texture or magnification - all in a single scan! Get the precision you need in a single acquisition without the limitations associated with traditional phase measuring interferometry.

FLEXIBILITY — A key component of the NewView 600s is its configurability. Based on an open architecture, the system easily accommodates a wide range of sample sizes, materials, and textures. Standard accessories include a complete line of high quality interferometric objectives, manual and motorized turrets, and sample positioning stages. Also, a convenient breadboard is available to accept application specific custom fixturing. Whether you need a versatile system with all the options, or a dedicated production setup, the NewView 600s can be configured to meet your needs.

SIMPLICITY — Many instruments claim to be easy to use but often fall short. Not the NewView 600! All measurements are fast, nondestructive and require no sample preparation. Areal surface data is rapidly acquired and processed, yielding more than 300,000 data points in seconds. Objectives are easily interchanged using quick-mount adapters or even faster when using a multi-position turret – providing you with the magnification, field-of-view, and resolution you need, when you need it. Ergonomically positioned coarse, medium, and fine focus knobs, an on-screen Live Display, and automatic light level adjustment expedite sample setup. With the NewView 600s, you won't find yourself continually reaching for frequently used controls.

CHARACTERIZATION — And of course, the system is powered by ZYGO's comprehensive metrology software package, MetroPro™, providing complete 3D and 2D surface characterization, visualization, and processing options. In addition to advanced analysis, user-friendly MetroPro includes instrument control, password protection, statistical databasing, programmable scripting, customizable layout, pass/fail criteria, and much more.

Not exactly sure what features you need today, or what you'll need tomorrow? The NewView 600s offers a full range of options and upgrades to meet your metrology and budgetary requirements, protecting your investment for years. From cost-effective bench-top research tools, to dedicated production systems and sensors, the NewView 600s optical profiler offers a complete metrology solution for today's leading-edge research and production applications.

Contact ZYGO today to arrange for a free analysis of your samples and a NewView 600 demonstration at a location near you!

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Covered by one or more of the following US patents: 4,948,253; 5,402,234; 5,398,113; 5,953,124; 5,784,164; 6,028,670; 6,597,460; 6,822,745; 6,775,006; and 6,714,307. Other US and foreign patents pending.

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